FORM PTO 1449 (modified)				ATTY DOCKET NO. 03560.002983	APPLICATION 10/050,787			
U.S. DEPARTMENT OF COMMERCE PE CONTROL PATENT AND TRADEMARK OFFICE PE CONTROL PER CONTROL				APPLICANT TOSHIHIRO YAMASHITA ET AL		MAR S	Elva	
(Use several sheets if necestary) MAR 1 3 2002				A	6	BOUP 5	2002 153	
			Tr. SE	U.S. PATENT DOCUMENTS	1		10 11	
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
SHV		6,051,851	04/18/00	Ohmi et al.	257	185		
SHV		6,273,955	08/14/01	Yoshino et al.	118	718		
SHV		6,338,872	01/15/02	Yoshino et al.	427	248.1		
SHV		6,113,732	09/05/00	Yoshida et al.	156	345		
SHV		6,335,281	01/01/02	Segi et al.	438	680		
SHV		5,232,507	08/03/93	Ohtoshi et al.	118	719		
SHV		6,223,684	05/01/01	Fujioka et al.	118	723		
SHV		6,103,442	08/15/00	Katagiri et al.	430	127		
SHV		5,360,484	11/01/94	Takai et al.	118	723		
SHV		5,597,623	01/28/97	Takai et al.	427	575		
SHV		6,158,382	12/12/00	Segi et al.	118	723		
ŠHV		4,356,073	10/26/82	McKelvey	204	192 R		
SHV		4,422,916	12/27/83	McKelvey	204	192 R		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
	JP	11 029863	02/02/99	Japan			Eng. Abst.	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
SHV		S. Schiller, et al. "Progress in the Application of the Plasma Emission Monitor in W b Coating" Pages 124-139.						
SHV								
EXAMINER		11 11 C.		DATE CONSIDERED				
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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